

United States Department of Commerce
National Institute of Standards and Technology



Certificate of Accreditation to ISO/IEC 17025:1999

NVLAP LAB CODE: 200129-0

AHD (Amber Helm Development, L.C.)
Dowagiac, MI

is recognized by the National Voluntary Laboratory Accreditation Program for conformance with criteria set forth in
NIST Handbook 150:2001 and all requirements of ISO/IEC 17025:1999.
Accreditation is granted for specific services, listed on the Scope of Accreditation, for:

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

2006-07-01 through 2007-06-30

Effective dates



Dolly S. Bruce

For the National Institute of Standards and Technology



SCOPE OF ACCREDITATION TO ISO/IEC 17025:1999

AHD (Amber Helm Development, L.C.)

92723 Michigan Highway 152

Dowagiac, MI 49047-8824

Mr. Gordon Helm

Phone: 269-429-8352 Fax: 269-429-9016

E-Mail: ghelm@ahde.com

URL: http://www.ahde.com

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

NVLAP LAB CODE 200129-0

NVLAP Code Designation / Description

Emissions Test Methods:

- 12/CIS22 IEC/CISPR 22 (1997) & EN 55022 (1998) + A1(2000): Limits and methods of measurement of radio disturbance characteristics of information technology equipment
12/CIS22a IEC/CISPR 22 (1993) and EN 55022 (1994): Limits and methods of measurement of radio disturbance characteristics of information technology equipment, Amendment 1 (1995) and Amendment 2 (1996)
12/FCC15b ANSI C63.4 (2003) with FCC Method 47 CFR Part 15, Subpart B: Unintentional Radiators (Limited to 1 GHZ)
12/T51 AS/NZS CISPR 22 (2002) and AS/NZS 3548 (1997): Electromagnetic Interference - Limits and Methods of Measurement of Information Technology Equipment

Immunity Test Methods:

- 12/I01 IEC 61000-4-2, Ed. 1.2 (2001) + A1, A2; EN 61000-4-2: Electrostatic Discharge Immunity Test
12/I04 IEC 61000-4-5, Ed. 1.1 (2001-04); EN 61000-4-5: Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test

2006-07-01 through 2007-06-30

Effective dates

Sally S. Bruce

For the National Institute of Standards and Technology